NA Traceability Committee Meeting Minutes

North America Spring Standards Meetings 2013
Thursday, 4 April, 2013, 3:00 PM - 5:00 PM
SEMI HQ, San Jose, CA

Next Committee Meeting
Thursday, July 11, 2013, San Francisco Marriott Marquis, CA in conjunction with SEMICON West. Check
www.semi.org/standards for the latest update.

Attendees:

SEMI Staff
Kevin Nguyen – SEMI NA

Co-chair – Yaw Obeng (NIST)

Table 1 – Meeting Attendees

Last Name	First Name	Company
Baylies	Win	BayTech Group
Brown	David	Intel
Iga	Yoichi	Renesas*
Obeng	Yaw	NIST*
Trego	James	James Trego*

*Attended via teleconference

Table 2 – Task Force Change

Group	Changes
Int'l Anti-Counterfeiting TF	TF was disbanded

Table 3 – Ballot Summary
None

Table 4 – Authorized Ballots

#	When	SC/TF/WG	Details
5581	Cycle 3-2013	NA Traceability Committee	Reapproval of SEMI T3-0302 (Reapproved 1108), Specification for Wafer Box Labels
5582	Cycle 3-2013	NA Traceability Committee	Reapproval of SEMI T4-0301 (Reapproved 0307), Specification for 150 mm and 200 mm Pod Identification Dimensions

Table 5 – Authorized Activities
Listing of all new TFOFs, SNARFs, and other activities approved by the committee.

#	Type	SC/TF/WG	Details
5581	SNARF	NA Traceability Committee	Reapproval of SEMI T3-0302 (Reapproved 1108), Specification for Wafer Box Labels
5582	SNARF	NA Traceability Committee	Reapproval of SEMI T4-0301 (Reapproved 0307), Specification for 150 mm and 200 mm Pod Identification Dimensions

Note: SNARFs and TFOFs are available for review on the SEMI Web site at:
http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF

Table 6 – Previous Meeting Actions Items
None

Table 7 – New Actions Items
None

1.0   Call to Order
Yaw Obeng called the meeting to order and welcomed everyone who attended. A round of self introduction was made. All SEMI standards meetings are subjected to SEMI Anti-Trust Reminder and Guidelines concerning Patentable Technology. SEMI Regulations now require all attendees to be members of SEMI standards. If not a member, please enroll at www.semi.org/standardsmembership. Agenda was reviewed and approved as written.

2.0   Review and Approval of the Meeting Minutes from the NA Fall, November 1, 2012, Meeting
Minutes were reviewed. No change was made.
Motion: To accept the minutes as corrected
By / 2ⁿᵈ: Dave Brown (INTEL)/Jim Trego (Consultant)
Discussion: None
Vote: Unanimous. Motion passed

Attachment – 1, NATraceabilityMinutes20121101

3.0   Staff Report
Staff report was presented by Kevin Nguyen.   Highlights.

- 2013 Event

Event Name	Event Details
SEMICON West	July 9-11, 2013 San Francisco, California
SEMICON Taiwan	September 4-6, 2013 Taipei
SEMICON Europa	October 8-10, 2013 Dresden, Germany

- West '13 Visitor Registration is now open.
  - The last day for FREE Expo Only badge (a $150 onsite value) is May 10.
  - Register today!
  - www.semiconwest.org
- Technical Ballot Critical Dates
  o Cycle 3, 2013
    - Ballot Submission Date: April 17
    - Voting Period Starts: May 1
    - Voting Period Ends: May 31
  o Cycle 4, 2013
    - Ballot Submission Date: May 20
    - Voting Period Starts: June 1
    - Voting Period Ends: July 1
- Major Items Included in Revision to the Regulations
  o This revision to the Regulations added a new category called Complementary File.
    - TC Chapters must take action on Standards that reference files in formats other than pdf (e.g., XML schema, WDSL, xls)
    - All non-pdf files published prior to March 2013 Regulations are Various Materials.

- TC Chapters must decide if non-pdf files are required for implementation of the Standard, and if so, TC Chapter must issue a ballot to make the non-pdf files "Complementary Files".
  - Elimination of Regional Standards
  - Exit mechanism from LOA in limbo
  - Clarification and additional guidance on Letter of Intent (LOI)
- March 2013 Publication Cycle
  - New Standards: 0
  - Revised Standards: 3
  - Reapproved Standards: 2
  - Withdrawn Standards: 0
    - Total SEMI Standards in portfolio: 871 (Includes 93 Inactive Standards)
- Standards Usage Interview
  - Looking for details on how standards are actually used:
  - Development/Engineering
  - Procurement
  - Manufacturing
  - Interview should take less than 30 minutes – contact James or any Standards staff
- The Official SEMI Standards Group
  - http://www.linkedin.com/groups/Official-SEMI-Standards-Group-1774298/about

Attachment – 2, SEMI Staff Report (Spring 2013) revB

4.0   Liaison Report

4.1 Japan Committee

Report was presented by Iga-san. Highlights are as follows:
- Last meeting
  - December 6, 2012
  - Int'l Conference Hall, Makuhari Messe, Chiba, Japan
- Next meeting
  - April 12, 2013
  - SEMI Japan, Tokyo, Japan
- Upcoming Ballot
  - Doc. 5487, New Standard: Specification for Basic Protocols to Support the Interoperation of Traceability Systems Necessary for Managing Product Identity throughout the Life Cycle of Objects Using Digital Signatures and Time Stamps
  - Is balloted in Cycle 2 and still needs more votes. The 30 days extension deadline is by April 20, 2013.
- Japan PV Traceability TF
  - Co-leaders
    - Yoichi Iga (Renesas Electronics)
    - Hirokazu Tsunobuchi (KEYENCE)
  - Charter
    - The objective is to define and elaborate several standards to unify PV traceability from the sliced wafer to the end of PV cell life－cycle.
  - Scope
    - The activities of the task force will result in the development of several industry standards where equipment suppliers, cell manufacturers, PV module manufacturers, PV users and other involved parties can find conformity, in any technical field of PV traceability. Initial work will focus on
      - Marking of ID to identify a product
      - Means to identify as a right product

- Security countermeasure to realize other Traceability depending on need
- Anti-Counterfeiting
  - Ballot
    - Doc. 5487, New Standard: Specification for Basic Protocols to Support the Interoperation of Traceability Systems Necessary for Managing Product Identity throughout the Life Cycle of Objects Using Digital Signatures and Time Stamps

Attachment – 3, JA_Trace_NA_Spring_R0.1

5.0 Ballots Review

There was no ballot to review.

6.0 Subcommittee & Task Force Reports

6.1 International Anti-Counterfeiting Task Force

Dave Brown reported this task force has been inactive for some time. The TF completed its objective in publishing SEMI T20, Specification for Authentication of Semiconductors and Related Products. All the semiconductor anti-counterfeiting standards activities are now in the SIA organization.

Motion: To disband the Int'l Anti-Counterfeiting TF
By / 2ⁿᵈ: Dave Brown (INTEL)/Win Baylies (BayTech Group)
Discussion: Iga-san, Jim and Yaw Obeng were all in favor of disbanding the task force.
Vote: Unanimous. Motion passed

6.2 ISO TC247, WG3

Dave Brown, chairman of TC247, reported ballot ISO 16678 "Anti-counterfeiting track and trace method using unique identifier numbering", which is similar to SEMI T20, was submitted. The standard was submitted to the secretary for translation into French. Translation process should be done within 6 weeks. For more information, contact Dave at david.a.brown@intel.com

7.0 Old Business
None

8.0 New Business

8.1 5 Year Review Standards

Kevin reported the following standards are due for 5 year review as required by the SEMI Regulations.
- SEMI T3-0302 (Reapproved 1108), Specification for Wafer Box Labels
- SEMI T4-0301 (Reapproved 0307), Specification for 150 mm and 200 mm Pod Identification Dimensions

Motion: To send SEMI T3 and T4 for reapproval ballot for review in San Francisco meeting.
By / 2ⁿᵈ: Dave Brown (INTEL)/Jim Trego (Consultant)
Discussion: None
Vote: Unanimous. Motion passed

8.2 Iga-san requested the following items to be added at the next committee meeting in San Francisco. Yaw Obeng and all other acknowledged his request. These items below will be discussed at the next meeting.
- T5487 Business Issue
- Iida san's new SNARF introduction
- Japan consortium Pilot demo For T5487

8.3 **Future NA Traceability Committee meeting.**

Yaw Obeng stated the attendance for the NA Spring and Fall meetings have been experiencing a low turnout. The NA Traceability committee is basically in the maintenance mode. There is no new standards activity. Therefore, he proposed this committee should only meet once year at SEMICON West unless there is an urgent need. All in attendance agreed with his proposal.

Going forward, unless there is an urgent standardization needs, the committee will only meet annually at SEMICON West.

9.0 Next Meeting
The next meeting of the NA Traceability committee is tentatively scheduled for Thursday, April 11, 2013 in San Francisco, CA in conjunction with SEMICON West 2013. Check www.semi.org/standards for the latest update.

10.0 Action Item Review

See table 7 above.

11.0 Adjourn
Adjournment of the meeting was held at 5:00 PM

These minutes are respectfully submitted by:

Kevin Nguyen,
SEMI NA Standards Committee Manager
Phone: 408-943-7997
Email: knguyen@semi.org

Approved by:
Yaw Obeng (NIST) – Co-chair   April 29, 2013

Table 7 – Index of Attachment Summary

#	Title
1	NATraceabilityMinutes20121101
2	SEMI Staff Report (Spring 2013) revB
3	JA_Trace_NA_Spring_R0.1

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Kevin Nguyen at the contact information above